

-12.352M

Tri-State (High Impedance)

Pin 1 Connection

Nominal Frequency

12.352MHz

TS

Duty Cycle 50 ±10(%)



Lead Integrity

Solderability

Vibration

Mechanical Shock

Resistance to Solvents

Temperature Cycling

Resistance to Soldering Heat

Frequency Tolerance/Stability ±100ppm Maximum

Package Operating Temperature Range 0°C to +70°C

MIL-STD-883, Method 2004

MIL-STD-202, Method 210

MIL-STD-202, Method 215

MIL-STD-883, Method 2003

MIL-STD-883, Method 1010

MIL-STD-202, Method 213, Condition C

MIL-STD-883, Method 2007, Condition A

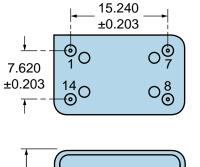
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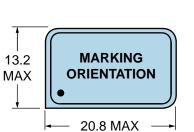
Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration) Aging at 25°C ±5ppm/year Maximum Operating Temperature Range 0°C to +70°C Supply Voltage 5.0Vdc ±10% Input Current 45mA Maximum Output Voltage Logic High (Voh) 2.4Vdc Minimum with TTL Load, Vdd-0.5Vdc Minimum with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load	ELECTRICAL SPECIFICA	TIONS	
Aging at 25°C ±5ppm/year Maximum Operating Temperature Range 0°C to +70°C Supply Voltage 5.0Vdc ±10% Input Current 45mA Maximum Output Voltage Logic High (Voh) 2.4Vdc Minimum with TTL Load, Vdd-0.5Vdc Minimum with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Duty Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vii) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A MIL-STD-883, Method 1014, Condition A	Nominal Frequency	12.352MHz	
Operating Temperature Range OPC to +70°C Supply Voltage 5.0Vdc ±10% Input Current 45mA Maximum Output Voltage Logic High (Voh) 2.4Vdc Minimum with TTL Load, Vdd-0.5Vdc Minimum with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMO Load) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Load Drive Capability 10TTL or 50pF HCMOS Load Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Frequency Tolerance/Stability	±100ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over th Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration)	
Supply Voltage 5.0Vdc ±10% Input Current 45mA Maximum Output Voltage Logic High (Voh) 2.4Vdc Minimum with TTL Load, Vdd-0.5Vdc Minimum with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load Rise/Fall Time 6nSec Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMOS Load) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Load Drive Capability 10TTL or 50pF HCMOS Load Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Aging at 25°C	-5ppm/year Maximum	
Input Current 45mA Maximum Output Voltage Logic High (Voh) 2.4Vdc Minimum with TTL Load, Vdd-0.5Vdc Minimum with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load Rise/Fall Time 6nSec Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMO Load) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Load Drive Capability 10TTL or 50pF HCMOS Load Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Operating Temperature Range	0°C to +70°C	
Output Voltage Logic High (Voh) 2.4Vdc Minimum with TTL Load, Vdd-0.5Vdc Minimum with HCMOS Load Output Voltage Logic Low (Vol) 0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load Rise/Fall Time 6nSec Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMO Load) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Load Drive Capability 10TTL or 50pF HCMOS Load Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) ±2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to ±125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Supply Voltage	5.0Vdc ±10%	
Output Voltage Logic Low (Vol) 0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load Rise/Fall Time 6nSec Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMOC Load) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Load Drive Capability 10TTL or 50pF HCMOS Load Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Input Current	45mA Maximum	
Rise/Fall Time 6nSec Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMC Load) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load) Load Drive Capability 10TTL or 50pF HCMOS Load Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Output Voltage Logic High (Voh)	2.4Vdc Minimum with TTL Load, Vdd-0.5Vdc Minimum with HCMOS Load	
Load)Duty Cycle50 ±10(%) (Measured at 1.4Vdc with TTL Load or at 50% of waveform with HCMOS Load)Load Drive Capability10TTL or 50pF HCMOS LoadOutput Logic TypeCMOSPin 1 ConnectionTri-State (High Impedance)Tri-State Input Voltage (Vih and Vil)+2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output.Absolute Clock Jitter±100pSec MaximumOne Sigma Clock Period Jitter±25pSec MaximumStart Up Time10mSec MaximumStorage Temperature Range-55°C to +125°CENVIRONMENTAL & MECHANICAL SPECIFICATIONSFine Leak TestMIL-STD-883, Method 1014, Condition A	Output Voltage Logic Low (Vol)	0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load	
Load Drive Capability 10TTL or 50pF HCMOS Load Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Rise/Fall Time	6nSec Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load, at 20% to 80% of waveform with HCMOS Load)	
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Tri-State Input Voltage (Vih and Vil) +2.2Vdc Minimum to enable output, +0.8Vdc to disable output (High Impedance), No connect to enable output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Output Logic Type	CMOS	
output. Absolute Clock Jitter ±100pSec Maximum One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Pin 1 Connection	Tri-State (High Impedance)	
One Sigma Clock Period Jitter ±25pSec Maximum Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Tri-State Input Voltage (Vih and Vil)		
Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Absolute Clock Jitter	±100pSec Maximum	
Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	One Sigma Clock Period Jitter	±25pSec Maximum	
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Start Up Time	10mSec Maximum	
Fine Leak Test MIL-STD-883, Method 1014, Condition A	Storage Temperature Range	-55°C to +125°C	
	ENVIRONMENTAL & MEC	HANICAL SPECIFICATIONS	
Gross Leak Test MIL-STD-883, Method 1014, Condition C	Fine Leak Test	MIL-STD-883, Method 1014, Condition A	
	Gross Leak Test	MIL-STD-883, Method 1014, Condition C	

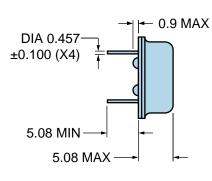
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MECHANICAL DIMENSIONS (all dimensions in millimeters)

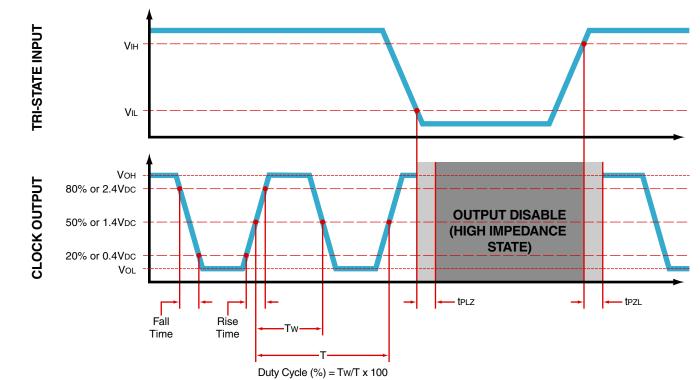






PIN	CONNECTION
1	Tri-State (High Impedance)
7	Ground/Case Ground
8	Output
14	Supply Voltage
LINE	MARKING
1	ECLIPTEK
2	EC11TS EC11=Product Series
3	12.352M
4	XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of Year ZZ=Week of Year

OUTPUT WAVEFORM & TIMING DIAGRAM





Frequency

Counter

RL

(Note 4)

Power

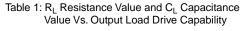
Supply

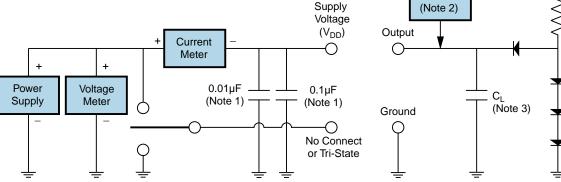
Oscilloscope

Probe

Test Circuit for TTL Output

Output Load Drive Capability	R _L Value (Ohms)	C _L Value (pF)
10TTL	390	15
5TTL	780	15
2TTL	1100	6
10LSTTL	2000	15
1TTL	2200	3





Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

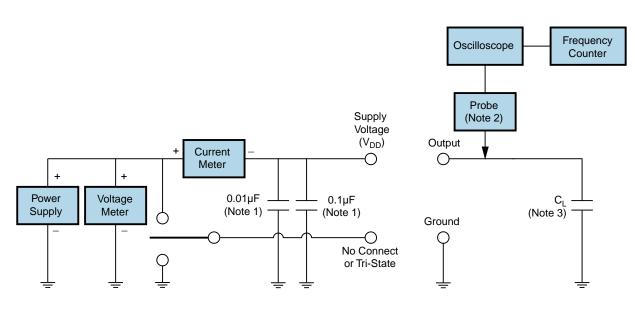
Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

Note 4: Resistance value RL is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.

Note 5: All diodes are MMBD7000, MMBD914, or equivalent.



Test Circuit for CMOS Output

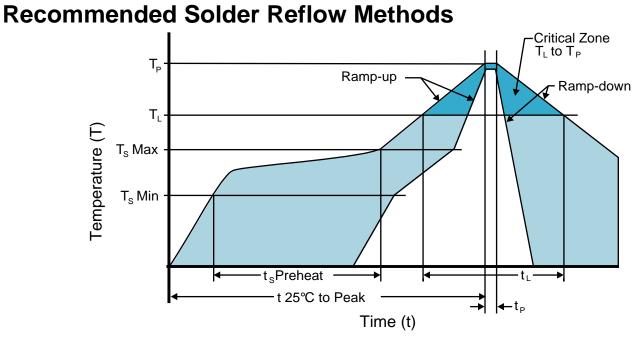


Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_1 includes sum of all probe and fixture capacitance.





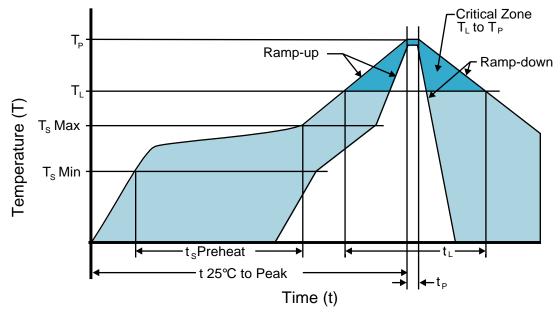
High Temperature Solder Bath (Wave Solder)

T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum	
Preheat		
- Temperature Minimum (Ts MIN)	150°C	
- Temperature Typical (T _s TYP)	175°C	
- Temperature Maximum (T _s MAX)	200°C	
- Time (t _s MIN)	60 - 180 Seconds	
Ramp-up Rate (T _L to T _P)	3°C/second Maximum	
Time Maintained Above:		
- Temperature (T∟)	217°C	
- Time (t∟)	60 - 150 Seconds	
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum	
Target Peak Temperature (T _P Target)	250°C +0/-5°C	
Time within 5°C of actual peak (t _p)	20 - 40 seconds	
Ramp-down Rate	6°C/second Maximum	
Time 25°C to Peak Temperature (t)	8 minutes Maximum	
Moisture Sensitivity Level	Level 1	
Additional Notes	Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option.	



Recommended Solder Reflow Methods

EC1100TS-12.352M



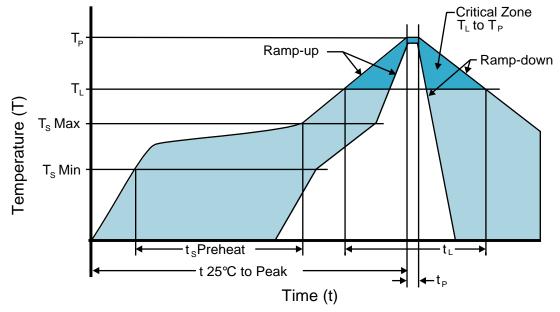
Low Temperature Infrared/Convection 185°C

T_s MAX to T_L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	N/A
 Temperature Typical (T_s TYP) 	150°C
- Temperature Maximum (T _s MAX)	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T _L to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	185°C Maximum
Target Peak Temperature (T _P Target)	185°C Maximum 2 Times
Time within 5°C of actual peak (t _p)	10 seconds Maximum 2 Times
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device. Use this method only for product with the Gull Wing option.



Recommended Solder Reflow Methods

EC1100TS-12.352M



Low Temperature Solder Bath (Wave Solder)

T _s MAX to T _L (Ramp-up Rate)	5°C/second Maximum	
Preheat		
- Temperature Minimum (Ts MIN)	N/A	
- Temperature Typical (T _s TYP)	150°C	
- Temperature Maximum (T _s MAX)	N/A	
- Time (t _s MIN)	30 - 60 Seconds	
Ramp-up Rate (T _L to T _P)	5°C/second Maximum	
Time Maintained Above:		
- Temperature (T∟)	150°C	
- Time (t∟)	200 Seconds Maximum	
Peak Temperature (T _P)	245°C Maximum	
Target Peak Temperature (T _P Target)	245°C Maximum 1 Time / 235°C Maximum 2 Times	
Time within 5°C of actual peak (t _P)	5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times	
Ramp-down Rate	5°C/second Maximum	
Time 25°C to Peak Temperature (t)	N/A	
Moisture Sensitivity Level	Level 1	
Additional Notes	Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option.	

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)